# E: Lattice Semiconductor Corporation - LFE3-70EA-7LFN672I Datasheet



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#### Understanding <u>Embedded - FPGAs (Field</u> <u>Programmable Gate Array)</u>

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

#### **Applications of Embedded - FPGAs**

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

#### Details

Product Status	Active
Number of LABs/CLBs	8375
Number of Logic Elements/Cells	67000
Total RAM Bits	4526080
Number of I/O	380
Number of Gates	-
Voltage - Supply	1.14V ~ 1.26V
Mounting Type	Surface Mount
Operating Temperature	-40°C ~ 100°C (TJ)
Package / Case	672-BBGA
Supplier Device Package	672-FPBGA (27x27)
Purchase URL	https://www.e-xfl.com/product-detail/lattice-semiconductor/lfe3-70ea-7lfn672i

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chain in order to better match the reference and feedback signals. This digital code from the ALU is also transmitted via the Digital Control bus (DCNTL) bus to its associated Slave Delay lines (two per DLL). The ALUHOLD input allows the user to suspend the ALU output at its current value. The UDDCNTL signal allows the user to latch the current value on the DCNTL bus.

The DLL has two clock outputs, CLKOP and CLKOS. These outputs can individually select one of the outputs from the tapped delay line. The CLKOS has optional fine delay shift and divider blocks to allow this output to be further modified, if required. The fine delay shift block allows the CLKOS output to phase shifted a further 45, 22.5 or 11.25 degrees relative to its normal position. Both the CLKOS and CLKOP outputs are available with optional duty cycle correction. Divide by two and divide by four frequencies are available at CLKOS. The LOCK output signal is asserted when the DLL is locked. Figure 2-5 shows the DLL block diagram and Table 2-5 provides a description of the DLL inputs and outputs.

The user can configure the DLL for many common functions such as time reference delay mode and clock injection removal mode. Lattice provides primitives in its design tools for these functions.



Figure 2-5. Delay Locked Loop Diagram (DLL)

\* This signal is not user accessible. This can only be used to feed the slave delay line.



# PLL/DLL Cascading

LatticeECP3 devices have been designed to allow certain combinations of PLL and DLL cascading. The allowable combinations are:

- PLL to PLL supported
- PLL to DLL supported

The DLLs in the LatticeECP3 are used to shift the clock in relation to the data for source synchronous inputs. PLLs are used for frequency synthesis and clock generation for source synchronous interfaces. Cascading PLL and DLL blocks allows applications to utilize the unique benefits of both DLLs and PLLs.

For further information about the DLL, please see the list of technical documentation at the end of this data sheet.

# **PLL/DLL PIO Input Pin Connections**

All LatticeECP3 devices contains two DLLs and up to ten PLLs, arranged in quadrants. If a PLL and a DLL are next to each other, they share input pins as shown in the Figure 2-7.

#### Figure 2-7. Sharing of PIO Pins by PLLs and DLLs in LatticeECP3 Devices



Note: Not every PLL has an associated DLL.

# **Clock Dividers**

LatticeECP3 devices have two clock dividers, one on the left side and one on the right side of the device. These are intended to generate a slower-speed system clock from a high-speed edge clock. The block operates in a ÷2, ÷4 or ÷8 mode and maintains a known phase relationship between the divided down clock and the high-speed clock based on the release of its reset signal. The clock dividers can be fed from selected PLL/DLL outputs, the Slave Delay lines, routing or from an external clock input. The clock divider outputs serve as primary clock sources and feed into the clock distribution network. The Reset (RST) control signal resets input and asynchronously forces all outputs to low. The RELEASE signal releases outputs synchronously to the input clock. For further information on clock dividers, please see TN1178, LatticeECP3 sysCLOCK PLL/DLL Design and Usage Guide. Figure 2-8 shows the clock divider connections.



### Figure 2-8. Clock Divider Connections



# **Clock Distribution Network**

LatticeECP3 devices have eight quadrant-based primary clocks and eight secondary clock/control sources. Two high performance edge clocks are available on the top, left, and right edges of the device to support high speed interfaces. These clock sources are selected from external I/Os, the sysCLOCK PLLs, DLLs or routing. These clock sources are fed throughout the chip via a clock distribution system.

## **Primary Clock Sources**

LatticeECP3 devices derive clocks from six primary source types: PLL outputs, DLL outputs, CLKDIV outputs, dedicated clock inputs, routing and SERDES Quads. LatticeECP3 devices have two to ten sysCLOCK PLLs and two DLLs, located on the left and right sides of the device. There are six dedicated clock inputs: two on the top side, two on the left side and two on the right side of the device. Figures 2-9, 2-10 and 2-11 show the primary clock sources for LatticeECP3 devices.

#### Figure 2-9. Primary Clock Sources for LatticeECP3-17



Note: Clock inputs can be configured in differential or single-ended mode.



as, overflow, underflow and convergent rounding, etc.

- Flexible cascading across slices to get larger functions
- RTL Synthesis friendly synchronous reset on all registers, while still supporting asynchronous reset for legacy users
- Dynamic MUX selection to allow Time Division Multiplexing (TDM) of resources for applications that require processor-like flexibility that enables different functions for each clock cycle

For most cases, as shown in Figure 2-24, the LatticeECP3 DSP slice is backwards-compatible with the LatticeECP2<sup>™</sup> sysDSP block, such that, legacy applications can be targeted to the LatticeECP3 sysDSP slice. The functionality of one LatticeECP2 sysDSP Block can be mapped into two adjacent LatticeECP3 sysDSP slices, as shown in Figure 2-25.



Figure 2-24. Simplified sysDSP Slice Block Diagram



# Programmable I/O Cells (PIC)

Each PIC contains two PIOs connected to their respective sysl/O buffers as shown in Figure 2-32. The PIO Block supplies the output data (DO) and the tri-state control signal (TO) to the sysl/O buffer and receives input from the buffer. Table 2-11 provides the PIO signal list.

#### Figure 2-32. PIC Diagram



\* Signals are available on left/right/top edges only.

\*\* Signals are available on the left and right sides only

\*\*\* Selected PIO.







Note: Simplified diagram does not show CE/SET/REST details.

## Output Register Block

The output register block registers signals from the core of the device before they are passed to the sysl/O buffers. The blocks on the left and right PIOs contain registers for SDR and full DDR operation. The topside PIO block is the same as the left and right sides except it does not support ODDRX2 gearing of output logic. ODDRX2 gearing is used in DDR3 memory interfaces. The PIO blocks on the bottom contain the SDR registers but do not support generic DDR.

Figure 2-34 shows the Output Register Block for PIOs on the left and right edges.

In SDR mode, OPOSA feeds one of the flip-flops that then feeds the output. The flip-flop can be configured as a Dtype or latch. In DDR mode, two of the inputs are fed into registers on the positive edge of the clock. At the next clock cycle, one of the registered outputs is also latched.

A multiplexer running off the same clock is used to switch the mux between the 11 and 01 inputs that will then feed the output.

A gearbox function can be implemented in the output register block that takes four data streams: OPOSA, ONEGA, OPOSB and ONEGB. All four data inputs are registered on the positive edge of the system clock and two of them are also latched. The data is then output at a high rate using a multiplexer that runs off the DQCLK0 and DQCLK1 clocks. DQCLK0 and DQCLK1 are used in this case to transfer data from the system clock to the edge clock domain. These signals are generated in the DQS Write Control Logic block. See Figure 2-37 for an overview of the DQS write control logic.

Please see TN1180, LatticeECP3 High-Speed I/O Interface for more information on this topic.

Further discussion on using the DQS strobe in this module is discussed in the DDR Memory section of this data sheet.



## SCI (SERDES Client Interface) Bus

The SERDES Client Interface (SCI) is an IP interface that allows the SERDES/PCS Quad block to be controlled by registers rather than the configuration memory cells. It is a simple register configuration interface that allows SERDES/PCS configuration without power cycling the device.

The Diamond and ispLEVER design tools support all modes of the PCS. Most modes are dedicated to applications associated with a specific industry standard data protocol. Other more general purpose modes allow users to define their own operation. With these tools, the user can define the mode for each quad in a design.

Popular standards such as 10Gb Ethernet, x4 PCI Express and 4x Serial RapidIO can be implemented using IP (available through Lattice), a single quad (Four SERDES channels and PCS) and some additional logic from the core.

The LatticeECP3 family also supports a wide range of primary and secondary protocols. Within the same quad, the LatticeECP3 family can support mixed protocols with semi-independent clocking as long as the required clock frequencies are integer x1, x2, or x11 multiples of each other. Table 2-15 lists the allowable combination of primary and secondary protocol combinations.

# Flexible Quad SERDES Architecture

The LatticeECP3 family SERDES architecture is a quad-based architecture. For most SERDES settings and standards, the whole quad (consisting of four SERDES) is treated as a unit. This helps in silicon area savings, better utilization and overall lower cost.

However, for some specific standards, the LatticeECP3 quad architecture provides flexibility; more than one standard can be supported within the same quad.

Table 2-15 shows the standards can be mixed and matched within the same quad. In general, the SERDES standards whose nominal data rates are either the same or a defined subset of each other, can be supported within the same quad. In Table 2-15, the Primary Protocol column refers to the standard that determines the reference clock and PLL settings. The Secondary Protocol column shows the other standard that can be supported within the same quad.

Furthermore, Table 2-15 also implies that more than two standards in the same quad can be supported, as long as they conform to the data rate and reference clock requirements. For example, a quad may contain PCI Express 1.1, SGMII, Serial RapidIO Type I and Serial RapidIO Type II, all in the same quad.

#### Table 2-15. LatticeECP3 Primary and Secondary Protocol Support

Primary Protocol	Secondary Protocol
PCI Express 1.1	SGMII
PCI Express 1.1	Gigabit Ethernet
PCI Express 1.1	Serial RapidIO Type I
PCI Express 1.1	Serial RapidIO Type II
Serial RapidIO Type I	SGMII
Serial RapidIO Type I	Gigabit Ethernet
Serial RapidIO Type II	SGMII
Serial RapidIO Type II	Gigabit Ethernet
Serial RapidIO Type II	Serial RapidIO Type I
CPRI-3	CPRI-2 and CPRI-1
3G-SDI	HD-SDI and SD-SDI



# LatticeECP3 Supply Current (Standby)<sup>1, 2, 3, 4, 5, 6</sup>

			Тур	Typical	
Symbol	Parameter	Device	-6L, -7L, -8L	-6, -7, -8	Units
		ECP-17EA	29.8	49.4	mA
		ECP3-35EA	53.7	89.4	mA
I <sub>CC</sub>	Core Power Supply Current	ECP3-70EA	137.3	230.7	mA
		ECP3-95EA	137.3	230.7	mA
		ECP3-150EA	219.5	370.9	mA
		ECP-17EA	18.3	19.4	mA
		ECP3-35EA	19.6	23.1	mA
I <sub>CCAUX</sub>	Auxiliary Power Supply Current	ECP3-70EA	26.5	32.4	mA
		ECP3-95EA	26.5	32.4	mA
		ECP3-150EA	37.0	45.7	mA
		ECP-17EA	0.0	0.0	mA
		ECP3-35EA	0.1	0.1	mA
I <sub>CCPLL</sub>	PLL Power Supply Current (Per PLL)	ECP3-70EA	0.1	0.1	mA
		ECP3-95EA	0.1	0.1	mA
		ECP3-150EA	0.1	0.1	mA
		ECP-17EA	1.3	1.4	mA
		ECP3-35EA	1.3	1.4	mA
I <sub>CCIO</sub>	Bank Power Supply Current (Per Bank)	ECP3-70EA	1.4	1.5	mA
		ECP3-95EA	1.4	1.5	mA
		ECP3-150EA	1.4	1.5	mA
I <sub>CCJ</sub>	JTAG Power Supply Current	All Devices	2.5	2.5	mA
		ECP-17EA	6.1	6.1	mA
		ECP3-35EA	6.1	6.1	mA
I <sub>CCA</sub>	Iransmit, Receive, PLL and Reference Clock Buffer Power Supply	ECP3-70EA	18.3	18.3	mA
		ECP3-95EA	18.3	18.3	mA
		ECP3-150EA	24.4	24.4	mA

# **Over Recommended Operating Conditions**

1. For further information on supply current, please see the list of technical documentation at the end of this data sheet.

2. Assumes all outputs are tristated, all inputs are configured as LVCMOS and held at the  $V_{\mbox{CCIO}}$  or GND.

3. Frequency 0 MHz.

4. Pattern represents a "blank" configuration data file.

5.  $T_J = 85$  °C, power supplies at nominal voltage.

6. To determine the LatticeECP3 peak start-up current data, use the Power Calculator tool.



# LatticeECP3 External Switching Characteristics (Continued)<sup>1, 2, 3, 13</sup>

			-	-8	-	-7	-	-6	
Parameter	Description	Device	Min.	Max.	Min.	Max.	Min.	Max.	Units
Generic DDRX2 In	puts with Clock and Data (>10bits	s wide) are Aligned at I	Pin (GDD	RX2_RX	.ECLK.A	ligned)	1		
(No CLKDIV)									
Left and Right Side	es Using DLLCLKPIN for Clock Ir			0.005	1	0.005	1	0.005	
<sup>t</sup> DVACLKGDDR	Data Setup Before CLK	ECP3-150EA		0.225		0.225		0.225	
	Data Hold After CLK	ECP3-150EA	0.775	-	0.775		0.775		
<sup>T</sup> MAX_GDDR	DDRX2 Clock Frequency	ECP3-150EA	_	460	_	385	_	345	MHZ
<sup>t</sup> DVACLKGDDR	Data Setup Before CLK	ECP3-70EA/95EA		0.225		0.225		0.225	UI
<sup>t</sup> DVECLKGDDR	Data Hold After CLK	ECP3-70EA/95EA	0.775	—	0.775		0.775	—	UI
fMAX_GDDR	DDRX2 Clock Frequency	ECP3-70EA/95EA		460		385		311	MHZ
t <sub>DVACLKGDDR</sub>	Data Setup Before CLK	ECP3-35EA	_	0.210	—	0.210	—	0.210	UI
t <sub>DVECLKGDDR</sub>	Data Hold After CLK	ECP3-35EA	0.790		0.790	—	0.790	_	UI
f <sub>MAX_GDDR</sub>	DDRX2 Clock Frequency	ECP3-35EA	_	460	_	385	_	311	MHz
t <sub>DVACLKGDDR</sub>	Data Setup Before CLK (Left and Right Sides)	ECP3-17EA	_	0.210	_	0.210		0.210	UI
t <sub>DVECLKGDDR</sub>	Data Hold After CLK	ECP3-17EA	0.790	—	0.790	—	0.790	—	UI
f <sub>MAX_GDDR</sub>	DDRX2 Clock Frequency	ECP3-17EA		460		385		311	MHz
Top Side Using PC	LK Pin for Clock Input								
t <sub>DVACLKGDDR</sub>	Data Setup Before CLK	ECP3-150EA		0.225		0.225		0.225	UI
t <sub>DVECLKGDDR</sub>	Data Hold After CLK	ECP3-150EA	0.775	—	0.775	—	0.775	_	UI
f <sub>MAX_GDDR</sub>	DDRX2 Clock Frequency	ECP3-150EA	_	235	—	170		130	MHz
t <sub>DVACLKGDDR</sub>	Data Setup Before CLK	ECP3-70EA/95EA	_	0.225	_	0.225	_	0.225	UI
t <sub>DVECLKGDDR</sub>	Data Hold After CLK	ECP3-70EA/95EA	0.775	—	0.775	—	0.775	_	UI
f <sub>MAX_GDDR</sub>	DDRX2 Clock Frequency	ECP3-70EA/95EA	_	235		170	—	130	MHz
t <sub>DVACLKGDDR</sub>	Data Setup Before CLK	ECP3-35EA	_	0.210		0.210		0.210	UI
t <sub>DVECLKGDDR</sub>	Data Hold After CLK	ECP3-35EA	0.790	—	0.790	—	0.790		UI
f <sub>MAX_GDDR</sub>	DDRX2 Clock Frequency	ECP3-35EA		235		170		130	MHz
t <sub>DVACLKGDDR</sub>	Data Setup Before CLK	ECP3-17EA		0.210		0.210		0.210	UI
t <sub>DVECLKGDDR</sub>	Data Hold After CLK	ECP3-17EA	0.790	—	0.790		0.790		UI
f <sub>MAX_GDDR</sub>	DDRX2 Clock Frequency	ECP3-17EA	_	235		170		130	MHz
Generic DDRX2 In Input	puts with Clock and Data (<10 Bit	ts Wide) Centered at P	in (GDDF	RX2_RX.I	DQS.Cen	tered) U	sing DQ	S Pin for	Clock
Left and Right Side	es								
t <sub>SUGDDR</sub>	Data Setup Before CLK	All ECP3EA Devices	330	_	330		352		ps
t <sub>HOGDDR</sub>	Data Hold After CLK	All ECP3EA Devices	330	—	330	—	352	_	ps
f <sub>MAX GDDR</sub>	DDRX2 Clock Frequency	All ECP3EA Devices	_	400	_	400	_	375	MHz
Generic DDRX2 In	puts with Clock and Data (<10 Bit	ts Wide) Aligned at Pin	(GDDR)	(2_RX.D0	QS.Align	ed) Using	g DQS Pi	n for Clo	ck Input
Left and Right Side	es								
t <sub>DVACLKGDDR</sub>	Data Setup Before CLK	All ECP3EA Devices	—	0.225	_	0.225	—	0.225	UI
t <sub>DVECLKGDDR</sub>	Data Hold After CLK	All ECP3EA Devices	0.775	—	0.775	—	0.775	_	UI
f <sub>MAX GDDR</sub>	DDRX2 Clock Frequency	All ECP3EA Devices	_	400	_	400	—	375	MHz
Generic DDRX1 O	utput with Clock and Data (>10 B	its Wide) Centered at P	in (GDD	RX1_TX.	SCLK.Ce	ntered)10	)		
t <sub>DVBGDDR</sub>	Data Valid Before CLK	ECP3-150EA	670	—	670		670		ps
t <sub>DVAGDDR</sub>	Data Valid After CLK	ECP3-150EA	670	<b>—</b>	670	<b>—</b>	670	<b>—</b>	ps
f <sub>MAX</sub> GDDR	DDRX1 Clock Frequency	ECP3-150EA	—	250	—	250	—	250	MHz
	Data Valid Before CLK	ECP3-70EA/95EA	666	—	665		664	—	ps
	Data Valid After CLK	ECP3-70EA/95EA	666		665		664		ps
BIAGDDIT	1	1		I		l			· ·

# Over Recommended Commercial Operating Conditions



# LatticeECP3 External Switching Characteristics (Continued)<sup>1, 2, 3, 13</sup>

		-8 -7 -6				-6			
Parameter	Description	Device	Min.	Max.	Min.	Max.	Min.	Max.	Units
f <sub>MAX GDDR</sub>	DDRX1 Clock Frequency	ECP3-70EA/95EA	_	250	_	250		250	MHz
t <sub>DVBGDDR</sub>	Data Valid Before CLK	ECP3-35EA	683	_	688		690	_	ps
t <sub>DVAGDDR</sub>	Data Valid After CLK	ECP3-35EA	683	—	688	—	690	_	ps
f <sub>MAX GDDR</sub>	DDRX1 Clock Frequency	ECP3-35EA	—	250	_	250	_	250	MHz
t <sub>DVBGDDR</sub>	Data Valid Before CLK	ECP3-17EA	683	_	688		690		ps
t <sub>DVAGDDR</sub>	Data Valid After CLK	ECP3-17EA	683	—	688	—	690	_	ps
f <sub>MAX GDDR</sub>	DDRX1 Clock Frequency	ECP3-17EA	—	250	_	250	_	250	MHz
Generic DDRX1 Ou	tput with Clock and Data Aligne	d at Pin (GDDRX1_TX.	SCLK.Ali	gned) <sup>10</sup>					
t <sub>DIBGDDR</sub>	Data Invalid Before Clock	ECP3-150EA	—	335	—	338	—	341	ps
t <sub>DIAGDDR</sub>	Data Invalid After Clock	ECP3-150EA	—	335	—	338		341	ps
f <sub>MAX</sub> GDDR	DDRX1 Clock Frequency	ECP3-150EA	_	250	_	250		250	MHz
	Data Invalid Before Clock	ECP3-70EA/95EA	_	339	_	343		347	ps
t <sub>DIAGDDB</sub>	Data Invalid After Clock	ECP3-70EA/95EA	_	339	_	343		347	ps
f <sub>MAX</sub> GDDR	DDRX1 Clock Frequency	ECP3-70EA/95EA	_	250	_	250		250	MHz
	Data Invalid Before Clock	ECP3-35EA		322		320		321	ps
	Data Invalid After Clock	ECP3-35EA	_	322	_	320		321	ps
f <sub>MAX GDDB</sub>	DDRX1 Clock Frequency	ECP3-35EA	_	250	_	250		250	MHz
	Data Invalid Before Clock	ECP3-17EA		322		320		321	ps
	Data Invalid After Clock	ECP3-17EA	_	322	_	320		321	ps
f <sub>MAX GDDB</sub>	DDRX1 Clock Frequency	ECP3-17EA	_	250	_	250		250	MHz
Generic DDRX1 Ou	Itput with Clock and Data (<10 B	its Wide) Centered at F	in (GDD	RX1_TX.	DQS.Cen	tered) <sup>10</sup>			
Left and Right Side	25		-			-			
t <sub>DVBGDDR</sub>	Data Valid Before CLK	ECP3-150EA	670		670		670	_	ps
t <sub>DVAGDDR</sub>	Data Valid After CLK	ECP3-150EA	670	_	670	_	670	_	ps
f <sub>MAX GDDB</sub>	DDRX1 Clock Frequency	ECP3-150EA	_	250	_	250	_	250	MHz
	Data Valid Before CLK	ECP3-70EA/95EA	657		652		650	_	ps
t <sub>DVAGDDR</sub>	Data Valid After CLK	ECP3-70EA/95EA	657	_	652		650	_	ps
f <sub>MAX GDDB</sub>	DDRX1 Clock Frequency	ECP3-70EA/95EA	_	250	_	250	_	250	MHz
	Data Valid Before CLK	ECP3-35EA	670		675		676	_	ps
t <sub>DVAGDDR</sub>	Data Valid After CLK	ECP3-35EA	670	—	675	—	676	_	ps
f <sub>MAX GDDR</sub>	DDRX1 Clock Frequency	ECP3-35EA	—	250	_	250	_	250	MHz
t <sub>DVBGDDR</sub>	Data Valid Before CLK	ECP3-17EA	670	—	670	—	670	_	ps
t <sub>DVAGDDR</sub>	Data Valid After CLK	ECP3-17EA	670	_	670	_	670	_	ps
f <sub>MAX</sub> GDDR	DDRX1 Clock Frequency	ECP3-17EA	_	250	_	250		250	MHz
Generic DDRX2 Ou	tput with Clock and Data (>10 B	its Wide) Aligned at Pi	n (GDDR	X2_TX.A	ligned)				
Left and Right Side	es								
t <sub>DIBGDDR</sub>	Data Invalid Before Clock	All ECP3EA Devices	—	200	—	210	_	220	ps
t <sub>DIAGDDR</sub>	Data Invalid After Clock	All ECP3EA Devices	—	200	—	210	—	220	ps
f <sub>MAX GDDR</sub>	DDRX2 Clock Frequency	All ECP3EA Devices	_	500	_	420	_	375	MHz
Generic DDRX2 Ou	tput with Clock and Data (>10 B	its Wide) Centered at P	in Using	DQSDL	L (GDDF	X2_TX.C	QSDLL.	Centered	)11
Left and Right Side	S								
t <sub>DVBGDDR</sub>	Data Valid Before CLK	All ECP3EA Devices	400		400		431	_	ps
t <sub>DVAGDDR</sub>	Data Valid After CLK	All ECP3EA Devices	400	—	400	—	432	—	ps
f <sub>MAX_GDDR</sub>	DDRX2 Clock Frequency	All ECP3EA Devices	—	400	—	400	—	375	MHz

# **Over Recommended Commercial Operating Conditions**



# LatticeECP3 Family Timing Adders<sup>1, 2, 3, 4, 5, 7</sup>

Buffer Type	Description	-8	-7	-6	Units
Input Adjusters					
LVDS25E	LVDS, Emulated, VCCIO = 2.5 V	0.03	-0.01	-0.03	ns
LVDS25	LVDS, VCCIO = 2.5 V	0.03	0.00	-0.04	ns
BLVDS25	BLVDS, Emulated, VCCIO = 2.5 V	0.03	0.00	-0.04	ns
MLVDS25	MLVDS, Emulated, VCCIO = 2.5 V	0.03	0.00	-0.04	ns
RSDS25	RSDS, VCCIO = 2.5 V	0.03	-0.01	-0.03	ns
PPLVDS	Point-to-Point LVDS	0.03	-0.01	-0.03	ns
TRLVDS	Transition-Reduced LVDS	0.03	0.00	-0.04	ns
Mini MLVDS	Mini LVDS	0.03	-0.01	-0.03	ns
LVPECL33	LVPECL, Emulated, VCCIO = 3.3 V	0.17	0.23	0.28	ns
HSTL18_I	HSTL_18 class I, VCCIO = 1.8 V	0.20	0.17	0.13	ns
HSTL18_II	HSTL_18 class II, VCCIO = 1.8 V	0.20	0.17	0.13	ns
HSTL18D_I	Differential HSTL 18 class I	0.20	0.17	0.13	ns
HSTL18D_II	Differential HSTL 18 class II	0.20	0.17	0.13	ns
HSTL15_I	HSTL_15 class I, VCCIO = 1.5 V	0.10	0.12	0.13	ns
HSTL15D_I	Differential HSTL 15 class I	0.10	0.12	0.13	ns
SSTL33_I	SSTL_3 class I, VCCIO = 3.3 V	0.17	0.23	0.28	ns
SSTL33_II	SSTL_3 class II, VCCIO = 3.3 V	0.17	0.23	0.28	ns
SSTL33D_I	Differential SSTL_3 class I	0.17	0.23	0.28	ns
SSTL33D_II	Differential SSTL_3 class II	0.17	0.23	0.28	ns
SSTL25_I	SSTL_2 class I, VCCIO = 2.5 V	0.12	0.14	0.16	ns
SSTL25_II	SSTL_2 class II, VCCIO = 2.5 V	0.12	0.14	0.16	ns
SSTL25D_I	Differential SSTL_2 class I	0.12	0.14	0.16	ns
SSTL25D_II	Differential SSTL_2 class II	0.12	0.14	0.16	ns
SSTL18_I	SSTL_18 class I, VCCIO = 1.8 V	0.08	0.06	0.04	ns
SSTL18_II	SSTL_18 class II, VCCIO = 1.8 V	0.08	0.06	0.04	ns
SSTL18D_I	Differential SSTL_18 class I	0.08	0.06	0.04	ns
SSTL18D_II	Differential SSTL_18 class II	0.08	0.06	0.04	ns
SSTL15	SSTL_15, VCCIO = 1.5 V	0.087	0.059	0.032	ns
SSTL15D	Differential SSTL_15	0.087	0.059	0.032	ns
LVTTL33	LVTTL, VCCIO = 3.3 V	0.07	0.07	0.07	ns
LVCMOS33	LVCMOS, VCCIO = 3.3 V	0.07	0.07	0.07	ns
LVCMOS25	LVCMOS, VCCIO = 2.5 V	0.00	0.00	0.00	ns
LVCMOS18	LVCMOS, VCCIO = 1.8 V	-0.13	-0.13	-0.13	ns
LVCMOS15	LVCMOS, VCCIO = 1.5 V	-0.07	-0.07	-0.07	ns
LVCMOS12	LVCMOS, VCCIO = 1.2 V	-0.20	-0.19	-0.19	ns
PCI33	PCI, VCCIO = 3.3 V	0.07	0.07	0.07	ns
Output Adjusters					
LVDS25E	LVDS, Emulated, VCCIO = 2.5 V	1.02	1.14	1.26	ns
LVDS25	LVDS, VCCIO = 2.5 V	-0.11	-0.07	-0.03	ns
BLVDS25	BLVDS, Emulated, VCCIO = 2.5 V	1.01	1.13	1.25	ns
MLVDS25	MLVDS, Emulated, VCCIO = 2.5 V	1.01	1.13	1.25	ns

#### **Over Recommended Commercial Operating Conditions**



# **DLL** Timing

## **Over Recommended Operating Conditions**

Parameter	Description	Condition	Min.	Тур.	Max.	Units
f <sub>REF</sub>	Input reference clock frequency (on-chip or off-chip)		133	—	500	MHz
f <sub>FB</sub>	Feedback clock frequency (on-chip or off-chip)		133	—	500	MHz
f <sub>CLKOP</sub> 1	Output clock frequency, CLKOP		133	—	500	MHz
f <sub>CLKOS</sub> <sup>2</sup>	Output clock frequency, CLKOS		33.3	—	500	MHz
t <sub>PJIT</sub>	Output clock period jitter (clean input)			—	200	ps p-p
	Output clock duty cycle (at 50% levels, 50% duty	Edge Clock	40		60	%
t <sub>DUTY</sub>	<ul> <li>echip)</li> <li>edback clock frequency (on-chip or off-chip)</li> <li>utput clock frequency, CLKOP</li> <li>utput clock frequency, CLKOS</li> <li>utput clock period jitter (clean input)</li> <li>utput clock duty cycle (at 50% levels, 50% duty cycle input clock, 50% duty cycle circuit turned f, time reference delay mode)</li> <li>utput clock duty cycle (at 50% levels, arbitrary ty cycle input clock, 50% duty cycle circuit nabled, time reference delay mode)</li> <li>utput clock duty cycle (at 50% levels, arbitrary ty cycle input clock, 50% duty cycle circuit nabled, time reference delay mode)</li> <li>utput clock duty cycle (at 50% levels, arbitrary ty cycle input clock, 50% duty cycle circuit nabled, clock injection removal mode) with DLI ascading</li> <li>utput clock to clock skew between two outputs ith the same phase setting</li> <li>nase error measured at device pads between f-chip reference clock and feedback clocks</li> <li>put clock minimum pulse width high (at 80% vel)</li> <li>put clock period jitter</li> </ul>	Primary Clock	30		70	%
	Output clock duty cycle (at 50% levels, arbitrary	Primary Clock < 250 MHz	45		55	%
t <sub>DUTYTRD</sub>	duty cycle input clock, 50% duty cycle circuit	Primary Clock ≥ 250 MHz	30		70	%
	enabled, time reference delay mode)	Edge Clock	45		55	%
	Output clock duty cycle (at 50% levels, arbitrary	Primary Clock < 250 MHz	40		60	%
t <sub>DUTYCIR</sub>	duty cycle input clock, 50% duty cycle circuit enabled clock injection removal mode) with DLL	Primary Clock ≥ 250 MHz	30		70	%
	cascading	Edge Clock	45		55	%
t <sub>SKEW</sub> <sup>3</sup>	Output clock to clock skew between two outputs with the same phase setting		_	—	100	ps
t <sub>PHASE</sub>	Phase error measured at device pads between off-chip reference clock and feedback clocks		_	—	+/-400	ps
t <sub>PWH</sub>	Input clock minimum pulse width high (at 80% level)		550	_	_	ps
t <sub>PWL</sub>	Input clock minimum pulse width low (at 20% level)		550	—	_	ps
t <sub>INSTB</sub>	Input clock period jitter			—	500	ps
t <sub>LOCK</sub>	DLL lock time		8	—	8200	cycles
t <sub>RSWD</sub>	Digital reset minimum pulse width (at 80% level)		3	—	—	ns
t <sub>DEL</sub>	Delay step size		27	45	70	ps
t <sub>RANGE1</sub>	Max. delay setting for single delay block (64 taps)		1.9	3.1	4.4	ns
t <sub>RANGE4</sub>	Max. delay setting for four chained delay blocks		7.6	12.4	17.6	ns

1. CLKOP runs at the same frequency as the input clock.

2. CLKOS minimum frequency is obtained with divide by 4.

3. This is intended to be a "path-matching" design guideline and is not a measurable specification.



#### Table 3-7. Channel Output Jitter

Description	Frequency	Min.	Тур.	Max.	Units
Deterministic	3.125 Gbps	—	—	0.17	UI, p-p
Random	3.125 Gbps	—	—	0.25	UI, p-p
Total	3.125 Gbps	—	—	0.35	UI, p-p
Deterministic	2.5 Gbps	—	—	0.17	UI, p-p
Random	2.5 Gbps	—	—	0.20	UI, p-p
Total	2.5 Gbps	—	—	0.35	UI, p-p
Deterministic	1.25 Gbps	—	—	0.10	UI, p-p
Random	1.25 Gbps	—	—	0.22	UI, p-p
Total	1.25 Gbps	—	—	0.24	UI, p-p
Deterministic	622 Mbps	—	—	0.10	UI, p-p
Random	622 Mbps	—	—	0.20	UI, p-p
Total	622 Mbps	—	—	0.24	UI, p-p
Deterministic	250 Mbps	—	—	0.10	UI, p-p
Random	250 Mbps	—	—	0.18	UI, p-p
Total	250 Mbps	—	—	0.24	UI, p-p
Deterministic	150 Mbps	—	—	0.10	UI, p-p
Random	150 Mbps	—	—	0.18	UI, p-p
Total	150 Mbps	—		0.24	UI, p-p

Note: Values are measured with PRBS 2<sup>7</sup>-1, all channels operating, FPGA logic active, I/Os around SERDES pins quiet, reference clock @ 10X mode.



## Figure 3-14. Jitter Transfer – 3.125 Gbps



Figure 3-15. Jitter Transfer – 2.5 Gbps





# Gigabit Ethernet/Serial Rapid I/O Type 1/SGMII/CPRI LV E.12 Electrical and Timing Characteristics

# AC and DC Characteristics

#### Table 3-17. Transmit

Symbol	Description	Test Conditions	Min.	Тур.	Max.	Units
T <sub>RF</sub>	Differential rise/fall time	20%-80%	—	80		ps
Z <sub>TX_DIFF_DC</sub>	Differential impedance		80	100	120	Ohms
J <sub>TX_DDJ</sub> <sup>3, 4, 5</sup>	Output data deterministic jitter		_	—	0.10	UI
J <sub>TX_TJ</sub> <sup>2, 3, 4, 5</sup>	Total output data jitter			_	0.24	UI

1. Rise and fall times measured with board trace, connector and approximately 2.5 pf load.

2. Total jitter includes both deterministic jitter and random jitter. The random jitter is the total jitter minus the actual deterministic jitter.

3. Jitter values are measured with each CML output AC coupled into a 50-Ohm impedance (100-Ohm differential impedance).

4. Jitter and skew are specified between differential crossings of the 50% threshold of the reference signal.

5. Values are measured at 1.25 Gbps.

#### Table 3-18. Receive and Jitter Tolerance

Symbol	Description	Test Conditions	Min.	Тур.	Max.	Units
RL <sub>RX_DIFF</sub>	Differential return loss	From 100 MHz to 1.25 GHz	10			dB
RL <sub>RX_CM</sub>	Common mode return loss	From 100 MHz to 1.25 GHz	6			dB
Z <sub>RX_DIFF</sub>	Differential termination resistance		80	100	120	Ohms
J <sub>RX_DJ</sub> <sup>1, 2, 3, 4, 5</sup>	Deterministic jitter tolerance (peak-to-peak)		_	_	0.34	UI
J <sub>RX_RJ</sub> <sup>1, 2, 3, 4, 5</sup>	Random jitter tolerance (peak-to-peak)		_		0.26	UI
J <sub>RX_SJ</sub> <sup>1, 2, 3, 4, 5</sup>	Sinusoidal jitter tolerance (peak-to-peak)		_		0.11	UI
J <sub>RX_TJ</sub> <sup>1, 2, 3, 4, 5</sup>	Total jitter tolerance (peak-to-peak)		_	_	0.71	UI
T <sub>RX_EYE</sub>	Receiver eye opening		0.29	_	_	UI

1. Total jitter includes deterministic jitter, random jitter and sinusoidal jitter. The sinusoidal jitter tolerance mask is shown in Figure 3-18.

2. Jitter values are measured with each high-speed input AC coupled into a 50-Ohm impedance.

3. Jitter and skew are specified between differential crossings of the 50% threshold of the reference signal.

4. Jitter tolerance, Differential Input Sensitivity and Receiver Eye Opening parameters are characterized when Full Rx Equalization is enabled.

5. Values are measured at 1.25 Gbps.



# SMPTE SD/HD-SDI/3G-SDI (Serial Digital Interface) Electrical and Timing Characteristics

# AC and DC Characteristics

#### Table 3-19. Transmit

Symbol	Description	Test Conditions	Min.	Тур.	Max.	Units
BR <sub>SDO</sub>	Serial data rate		270	—	2975	Mbps
T <sub>JALIGNMENT</sub> <sup>2</sup>	Serial output jitter, alignment	270 Mbps	—	—	0.20	UI
T <sub>JALIGNMENT</sub> <sup>2</sup>	Serial output jitter, alignment	1485 Mbps	—	—	0.20	UI
T <sub>JALIGNMENT</sub> <sup>1, 2</sup>	Serial output jitter, alignment	2970Mbps	—	—	0.30	UI
T <sub>JTIMING</sub>	Serial output jitter, timing	270 Mbps	—	—	0.20	UI
T <sub>JTIMING</sub>	Serial output jitter, timing	1485 Mbps	—	—	1.0	UI
T <sub>JTIMING</sub>	Serial output jitter, timing	2970 Mbps	—	—	2.0	UI

Notes:

 Timing jitter is measured in accordance with SMPTE RP 184-1996, SMPTE RP 192-1996 and the applicable serial data transmission standard, SMPTE 259M-1997 or SMPTE 292M (proposed). A color bar test pattern is used. The value of f<sub>SCLK</sub> is 270 MHz or 360 MHz for SMPTE 259M, 540 MHz for SMPTE 344M or 1485 MHz for SMPTE 292M serial data rates. See the Timing Jitter Bandpass section.

2. Jitter is defined in accordance with SMPTE RP1 184-1996 as: jitter at an equipment output in the absence of input jitter.

3. All Tx jitter is measured at the output of an industry standard cable driver; connection to the cable driver is via a 50 Ohm impedance differential signal from the Lattice SERDES device.

4. The cable driver drives: RL=75 Ohm, AC-coupled at 270, 1485, or 2970 Mbps, RREFLVL=RREFPRE=4.75 kOhm 1%.

#### Table 3-20. Receive

Symbol	Description	Test Conditions	Min.	Тур.	Max.	Units
BR <sub>SDI</sub>	Serial input data rate		270	—	2970	Mbps
CID	Stream of non-transitions (=Consecutive Identical Digits)		7(3G)/26(SMPTE Triple rates) @ 10-12 BER		_	Bits

#### Table 3-21. Reference Clock

Symbol	Description	Test Conditions	Min.	Тур.	Max.	Units
F <sub>VCLK</sub>	Video output clock frequency		27	_	74.25	MHz
DCV	Duty cycle, video clock		45	50	55	%



### Figure 3-21. sysCONFIG Parallel Port Write Cycle



1. In Master Parallel Mode the FPGA provides CCLK (MCLK). In Slave Parallel Mode the external device provides CCLK.

#### Figure 3-22. sysCONFIG Master Serial Port Timing









# sysl/O Differential Electrical Characteristics

# Transition Reduced LVDS (TRLVDS DC Specification)

### **Over Recommended Operating Conditions**

Symbol	Description	Min.	Nom.	Max.	Units
V <sub>CCO</sub>	Driver supply voltage (+/- 5%)	3.14	3.3	3.47	V
V <sub>ID</sub>	Input differential voltage	150	_	1200	mV
V <sub>ICM</sub>	Input common mode voltage	3	_	3.265	V
V <sub>CCO</sub>	Termination supply voltage	3.14	3.3	3.47	V
R <sub>T</sub>	Termination resistance (off-chip)	45	50	55	Ohms

Note: LatticeECP3 only supports the TRLVDS receiver.



## Mini LVDS

### **Over Recommended Operating Conditions**

Parameter Symbol	Description	Min.	Тур.	Max.	Units
Z <sub>O</sub>	Single-ended PCB trace impedance	30	50	75	Ohms
R <sub>T</sub>	Differential termination resistance	50	100	150	Ohms
V <sub>OD</sub>	Output voltage, differential,  V <sub>OP</sub> - V <sub>OM</sub>	300	_	600	mV
V <sub>OS</sub>	Output voltage, common mode, $ V_{OP} + V_{OM} /2$	1	1.2	1.4	V
$\Delta V_{OD}$	Change in V <sub>OD</sub> , between H and L	—	_	50	mV
$\Delta V_{ID}$	Change in $V_{OS}$ , between H and L	—	_	50	mV
V <sub>THD</sub>	Input voltage, differential,  V <sub>INP</sub> - V <sub>INM</sub>	200	_	600	mV
V <sub>CM</sub>	Input voltage, common mode, $ V_{INP} + V_{INM} /2$	0.3+(V <sub>THD</sub> /2)	_	2.1-(V <sub>THD</sub> /2)	
T <sub>R</sub> , T <sub>F</sub>	Output rise and fall times, 20% to 80%	—	_	550	ps
T <sub>ODUTY</sub>	Output clock duty cycle	40	—	60	%

Note: Data is for 6 mA differential current drive. Other differential driver current options are available.



# Point-to-Point LVDS (PPLVDS)

#### Over Recommended Operating Conditions

Description	Min.	Тур.	Max.	Units
Output driver supply $(1/-5\%)$	3.14	3.3	3.47	V
	2.25	2.5	2.75	V
Input differential voltage	100	—	400	mV
Input common mode voltage	0.2	—	2.3	V
Output differential voltage	130	—	400	mV
Output common mode voltage	0.5	0.8	1.4	V

## RSDS

#### **Over Recommended Operating Conditions**

Parameter Symbol	Description	Min.	Тур.	Max.	Units
V <sub>OD</sub>	Output voltage, differential, R <sub>T</sub> = 100 Ohms	100	200	600	mV
V <sub>OS</sub>	Output voltage, common mode	0.5	1.2	1.5	V
I <sub>RSDS</sub>	Differential driver output current	1	2	6	mA
V <sub>THD</sub>	Input voltage differential	100	—	-	mV
V <sub>CM</sub>	Input common mode voltage	0.3	—	1.5	V
T <sub>R</sub> , T <sub>F</sub>	Output rise and fall times, 20% to 80%	—	500		ps
T <sub>ODUTY</sub>	Output clock duty cycle	35	50	65	%

Note: Data is for 2 mA drive. Other differential driver current options are available.



# LatticeECP3 Family Data Sheet Supplemental Information

#### February 2014

#### Data Sheet DS1021

# **For Further Information**

A variety of technical notes for the LatticeECP3 family are available on the Lattice website at <u>www.latticesemi.com</u>.

- TN1169, LatticeECP3 sysCONFIG Usage Guide
- TN1176, LatticeECP3 SERDES/PCS Usage Guide
- TN1177, LatticeECP3 sysIO Usage Guide
- TN1178, LatticeECP3 sysCLOCK PLL/DLL Design and Usage Guide
- TN1179, LatticeECP3 Memory Usage Guide
- TN1180, LatticeECP3 High-Speed I/O Interface
- TN1181, Power Consumption and Management for LatticeECP3 Devices
- TN1182, LatticeECP3 sysDSP Usage Guide
- TN1184, LatticeECP3 Soft Error Detection (SED) Usage Guide
- TN1189, LatticeECP3 Hardware Checklist
- TN1215, LatticeECP2MS and LatticeECP2S Devices
- TN1216, LatticeECP2/M and LatticeECP3 Dual Boot Feature Advanced Security Encryption Key Programming Guide for LatticeECP3
- TN1222, LatticeECP3 Slave SPI Port User's Guide

For further information on interface standards refer to the following websites:

- JEDEC Standards (LVTTL, LVCMOS, SSTL, HSTL): www.jedec.org
- PCI: www.pcisig.com

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